



## Advanced Ultrafast Imaging

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### Message from the Guest Editors

Dear Colleagues,

Ultrafast imaging is a powerful tool for studying fast dynamics in nature and also for analyzing fast processes in industrial applications. To address the high demand for scientific research and technological development, various ultrafast imaging methods have been developed over the last 150 years. Particularly in recent years, new principles, materials, devices and systems for performing ultrafast image acquisition have been developed in diverse research fields including optics, semiconductors, information science, accelerators, biology, and so on. In addition, new imaging concepts based on ultrafast measurements have been proposed not to provide fast imaging speed, but to provide unique information about the target.

This Special Issue “Advanced Ultrafast Imaging” aims to reflect recent developments in ultrafast imaging technology, and to grasp the essence of ultrafast imaging for developing future devices and methods.





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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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